

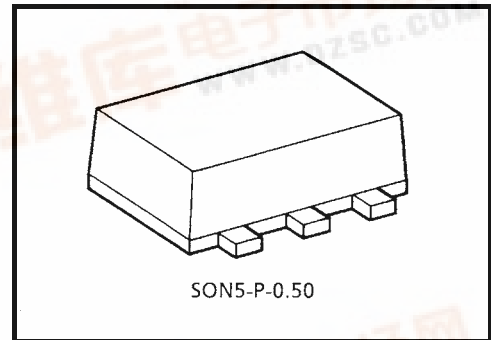
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7SH02FE

2 Input NOR Gate

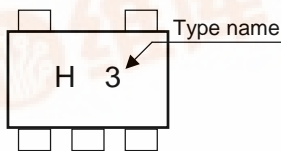
Features

- Super high speed operation : $t_{PD} = 3.6 \text{ ns (typ.)}$
@ $V_{CC} = 5 \text{ V}$
- Low power dissipation : $I_{CC} = 2 \mu\text{A (Max.)}$
@ $T_a = 25^\circ\text{C}$
- High noise immunity : $V_{NIH} = V_{NIH}$
 $= 28\% V_{CC} \text{ (Min.)}$
- 5.5V tolerant input.
- Wide operation voltage range : $V_{CC} \text{ (opr)} = 2\sim 5.5 \text{ V}$

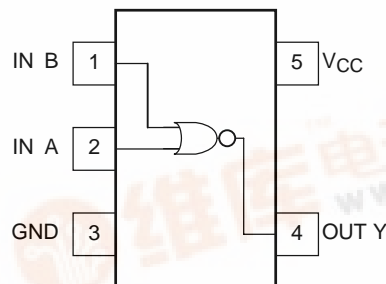


Weight: 0.003 g (typ.)

Marking



Pin Assignment (top view)

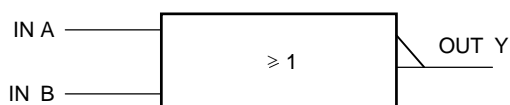


Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5~7	V
DC input voltage	V_{IN}	-0.5~7	V
DC output voltage	V_{OUT}	-0.5- $V_{CC} + 0.5$	V
Input diode current	I_{IK}	-20	mA
Output diode current	I_{OK}	± 20	mA
DC output current	I_{OUT}	± 25	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	150	mW
Storage temperature	T_{stg}	-65~150	$^\circ\text{C}$



Logic Diagram



Truth Table

A	B	Y
L	L	H
L	H	L
H	L	L
H	H	L

Recommended Operating Conditions

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2~5.5	V
Input voltage	V_{IN}	0~5.5	V
Output voltage	V_{OUT}	0~ V_{CC}	V
Operating temperature	T_{opr}	-40~85	°C
Input rise and fall time	dt/dv	0~100 ($V_{CC} = 3.3 V \pm 0.3 V$)	ns/V
		0~20 ($V_{CC} = 5 V \pm 0.5 V$)	

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Circuit	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		Unit		
				V_{CC} (V)	Min	Typ.	Max	Min		Max	
High-level input voltage	V_{IH}	—	—	2.0	1.5	—	—	1.5	—	V	
				3.0~5.5	$V_{CC} \times 0.7$	—	—	$V_{CC} \times 0.7$	—		
Low-level input voltage	V_{IL}	—	—	2.0	—	—	0.5	—	0.5	V	
				3.0~5.5	—	—	$V_{CC} \times 0.3$	—	$V_{CC} \times 0.3$		
High-level output voltage	V_{OH}	—	$V_{IN} = V_{IL}$	$I_{OH} = -50 \mu\text{A}$	2.0	1.9	2.0	—	1.9	—	V
					3.0	2.9	3.0	—	2.9	—	
				$I_{OH} = -4 \text{ mA}$	3.0	2.58	—	—	2.48	—	
					4.5	3.94	—	—	3.80	—	
Low-level output voltage	V_{OL}	—	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 50 \mu\text{A}$	2.0	—	0	0.1	—	0.1	V
					3.0	—	0	0.1	—	0.1	
				$I_{OL} = 4 \text{ mA}$	3.0	—	—	0.36	—	0.44	
					4.5	—	—	0.36	—	0.44	
Input leakage current	I_{IN}	—	$V_{IN} = 5.5 \text{ V}$ or GND	0~5.5	—	—	± 0.1	—	± 1.0	μA	
Quiescent supply current	I_{CC}	—	$V_{IN} = V_{CC}$ or GND	5.5	—	—	2.0	—	20.0	μA	

AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
		V _{CC} (V)	C _L (pF)	Min	Typ.	Max	Min	Max	
Propagation delay time	t _{PLH}	3.3 ± 0.3	15	—	5.6	7.9	1.0	9.5	ns
			50	—	8.1	11.4	1.0	13.0	
	t _{PHL}	5.0 ± 0.5	15	—	3.6	5.5	1.0	6.5	
			50	—	5.1	7.5	1.0	8.5	
Input capacitance	C _{IN}			—	4	10	—	10	pF
Power dissipation capacitance	C _{PD}	(Note)		—	15	—	—	—	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

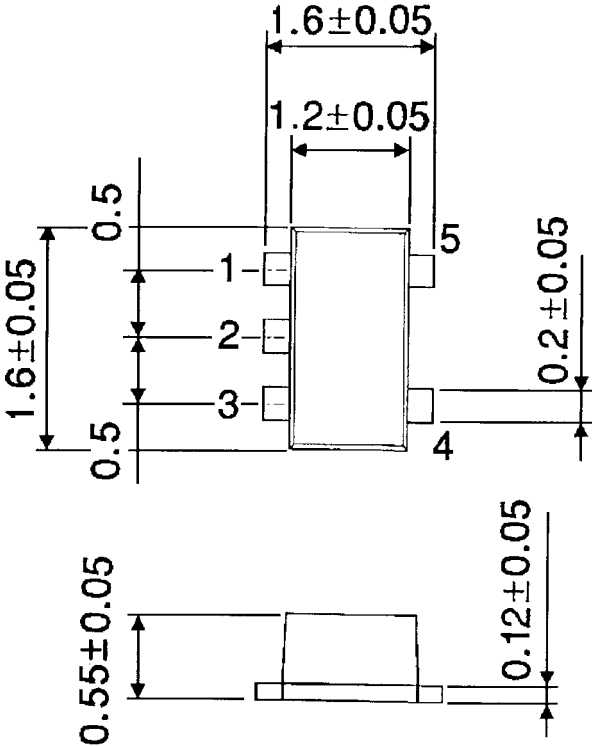
Average operating current can be obtained by the equation.

$$I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Package Dimensions

SON5-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

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